

Search Notes**Application/Control No.**

10/662,164

Examiner

Maikhanh Nguyen

Applicant(s)/Patent under Reexamination

CHENG ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	530	5/1/2006	MK
713	161,165	5/1/2006	MK
713	166,170	5/1/2006	MK
713	176	5/1/2006	MK
707	10	5/1/2006	MK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Name Search	5/1/2006	MK
West Search (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB)	5/1/2006	MK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner